SN54S260, SN74S260 DUAL 5-INPUT POSITIVE-NOR GATES

SDLS208

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 Package Options Include Ceramic Chip Carriers and Flat Packages in Addition to Plastic and Ceramic DIPs

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description

These devices contain two independent 5-input positive -NOR gates. They perform the Boolean function $Y = \overline{A + B + C + D + E}$ in positive logic.

The SN54S260 is characterized for operation over the full military temperature range of -55° C to 125° C. The SN74S260 is characterized for operation from 0°C to 70°C.

logic diagram (each gate)



logic symbol[†]



[†]This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J. N, and W packages.

SN548260 . . . J OR W PACKAGE SN74S260 . . . D OR N PACKAGE (TOP VIEW)

1	$\overline{\bigcup}$ 14	bvcc
2	13	1E
3	12	םום
4	11	2E
5	10	2D
6	9	2C
7	8]2B
	3 4 5	2 13 3 12 4 11 5 10

SN54S260 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

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SN54S260, SN74S260 DUAL 5-INPUT POSITIVE-NOR GATES

schematic (each gate)



Resistor values shown are nominal. The portion of the schematic within the deshed-line is repeated for each additional input.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V _{CC} (see Note 1)		7 V
	SN54'	
	SN74'	0°C to 70°C
Storage temperature range		-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.



recommended operating conditions

		s	SN54\$260			SN74S260			
		MIN	TYP	MAX	MIN	ТҮР	MAX	UNIT	
Vcc	Supply voltage	4.5	5	5.5	4.75	5	5.25	v	
VIH	High-level input voltage	2			2			V	
VIL	Low-level input voltage			0.8			0.8	V	
юн	High-level output current			- 1			- 1	mΑ	
I OL	Low-level output current			20			20	mA	
TA	Operating free-air temperature	- 55		125	0		70	°C	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS *		SN54S260			SN74S260				
			MIN	түр‡	МАХ	MIN	түр‡	MAX	UNIT	
 Viк	V _{CC} = MIN,	I _I = 18 mA				- 1.2			- 1.2	V
VOH	V _{CC} = MIN,	V _{1L} = 0.8 V,	I _{OH} = 1 mA	2.5	3.4		2.7	3.4		V
VQL	V _{CC} = MIN,	VIH = 2 V,	IOL = 20 mA			0.5			0.5	V
II	V _{CC} = MAX.	V ₁ = 5.5 V				1			1	mA
	V _{CC} = MAX,	V _{1H} = 2.7 V				50			50	μA
	V _{CC} = MAX,	V _{IL} = 0.5 V				- 2			- 2	mA
IOSS	V _{CC} = MAX			- 40		- 100	- 40	_	- 100	mΑ
ССН	V _{CC} = MAX,	V = 0 V			17	29		17	29	mΑ
ICCL	V _{CC} = MAX,	See Note 2			26	45		26	45	mΑ

+ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.

§Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second. NOTE 2: One input at 4.5 V, all others at GND.

switching characteristics, V_{CC} = 5 V, T_A = 25° C (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CON	MIN	түр	МАХ	UNIT	
1PLH	Acu	v	B. = 290 O	<u> </u>		4	5.5	ris
tPHL	Any Y	ni - 200 sz,	R _L = 280 Ω, C _L = 15 pF		4	6	пs	

NOTE 3: See General Information Section for load circuits and voltage waveforms.



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